

L Number	Hits	Search Text	DB	Time stamp
37	7	((lower or top or bottom or upper or first or second) near substrate) near10 (bond or bonding or bonded) and pixel and ((test or testing or tested) near2 pad)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:39
38	342	substrate.clm. and ((test or testing) near2 pad).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:39
39	9	substrate.clm. and ((test or testing) near2 pad).clm. and (data near pad).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:40
40	14	substrate.clm. and ((test or testing) near2 pad).clm. and (data near2 pad).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:40
41	4	substrate.clm. and ((test or testing) near2 pad).clm. and (data near2 pad).clm. and pixel.clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:43
42	29	(data near pad) and (gate near pad) and ((test or testing) near2 pad)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:43
43	26	(data near pad) same (gate near pad) and ((test or testing) near2 pad)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:43
44	15	(data near pad) same (gate near pad) same ((test or testing) near2 pad)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:44
45	6	(data near pad) same (gate near pad) same ((test or testing) near2 data near pad)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:45
46	15	(data near pad) same (gate near pad) same ((test or testing) near2 pad)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:45

47	5	<b>(data near pad) same (gate near pad) same ((test or testing) near2 pad) and on/off</b>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:47
48	1	<b>(data near2 on/off near2 (test or testing or tested) near2 pad)</b>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:47
49	12	<b>testing near2 data near2 pad</b>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:48
50	152	<b>(test or testing) near2 data near2 pad</b>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:48
51	43	<b>(test or testing) near data near pad</b>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:48
52	5	<b>((test or testing) near data near pad) and ((test or testing) near gate near pad)</b>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:51
53	4	<b>((test or testing) near data near pad) and ((test or testing) near gate near pad) and (data adj pad)</b>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 16:51